

### **IGBT 3 Chip**

### Features:

- 600V Trench & Field Stop technology
- low V<sub>CE(sat)</sub>
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling
- Qualified according to JEDEC for target applications

#### Recommended for:

- power module
- discrete components

#### **Applications:**

- drives
- white goods
- resonant applications



Chip Type	Chip Type V <sub>CE</sub> I <sub>Cn<sup>1)</sup></sub>		Die Size	Package
SIGC19T60SE	600V	600V 40A 4.84 x 3.98 mm <sup>2</sup>		sawn on foil

<sup>&</sup>lt;sup>1)</sup>nominal collector current at Tc = 100°C, not subject to production test - verified by design/characterization

### **Mechanical Parameters**

Die size		4.84 x 3.98		
Emitter pad size (incl.	gate pad)	See chip drawing		
Gate pad size		0.608 x 0.646		
Area total		19.26		
Thickness		70	μm	
Wafer size		200	mm	
Max.possible chips pe	er wafer	1403		
Passivation frontside		Photoimide		
Pad metal		3200 nm AlSiCu		
Backside metal		Ni Ag –system		
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond		AI, <500μm		
Reject ink dot size		Ø 0.65mm ; max 1.2mm		
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, Temperature 17°C – 2 < 6 month	ture 17°C – 25°C,	
	for open MBB bags	Acc. to IEC62258-3: Atmosphere >99% Nitrogen or inert Humidity <25%RH, Temperature 17°C – 25°C, < 6 mo		



### **Maximum Ratings**

Parameter	Symbol	Value	Unit
Collector-Emitter voltage, $T_{\rm vj}$ =25 °C	V <sub>CE</sub>	600	V
DC collector current, limited by $T_{\rm vj\ max}$	Ic	1)	Α
Pulsed collector current, $t_p$ limited by $T_{vj \max}^{2}$	$I_{c,puls}$	120	Α
Gate emitter voltage	V <sub>GE</sub>	±20	V
Operating junction temperature	T <sub>vj</sub>	-40 <b>+</b> 150	°C
Short circuit data $^{2)3)}$ $V_{GE}$ = 15V, $V_{CC}$ = 380V, $T_{Vj}$ = 150°C	tsc	5	μs

<sup>1)</sup> depending on thermal properties of assembly

### Static Characteristics (tested on wafer), $T_{vj}$ =25 °C

Parameter	Symbol	Conditions	Value			Unit
. diameter	- Cymbol	Conditions	min.	typ.	max.	01
Collector-Emitter breakdown voltage	V <sub>(BR)CES</sub>	$V_{\rm GE}$ =0V , $I_{\rm C}$ =2 mA	600			
Collector-Emitter saturation voltage	V <sub>CEsat</sub>	V <sub>GE</sub> =15V, I <sub>C</sub> =40A	1.13	1.55	1.97	V
Gate-Emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =0.58mA , $V_{\rm GE}$ = $V_{\rm CE}$	4.2	4.9	5.6	
Zero gate voltage collector current	I <sub>CES</sub>	V <sub>CE</sub> =600V , V <sub>GE</sub> =0V			1.6	μA
Gate-Emitter leakage current	I <sub>GES</sub>	$V_{\text{CE}}$ =0V , $V_{\text{GE}}$ =20V			300	nA
Integrated gate resistor	$r_{\rm G}$			none		Ω

### Electrical Characteristics (not subject to production test - verified by design / characterization)

Parameter	Symbol	Conditions	Value			Unit
raiailletei			min.	typ.	max.	Oilit
Collector-Emitter saturation voltage	V	$V_{\rm GE}$ =15V, $I_{\rm C}$ =40A,		1.9		V
Collector-Emitter Saturation voltage	$V_{CEsat}$	<i>T</i> <sub>vj</sub> =175 °C		1.9		V
Input capacitance	Cies	V <sub>CE</sub> =25V,		2423		
Output capacitance	Coes	V <sub>GE</sub> =0V, <i>f</i> =1MHz		113		pF
Reverse transfer capacitance	Cres	<i>T</i> <sub>vj</sub> =25 °C		72		

<sup>&</sup>lt;sup>2)</sup> not subject to production test - verified by design/characterization

<sup>&</sup>lt;sup>3)</sup> allowed number of short circuits: <1000; time between short circuits: >1s.



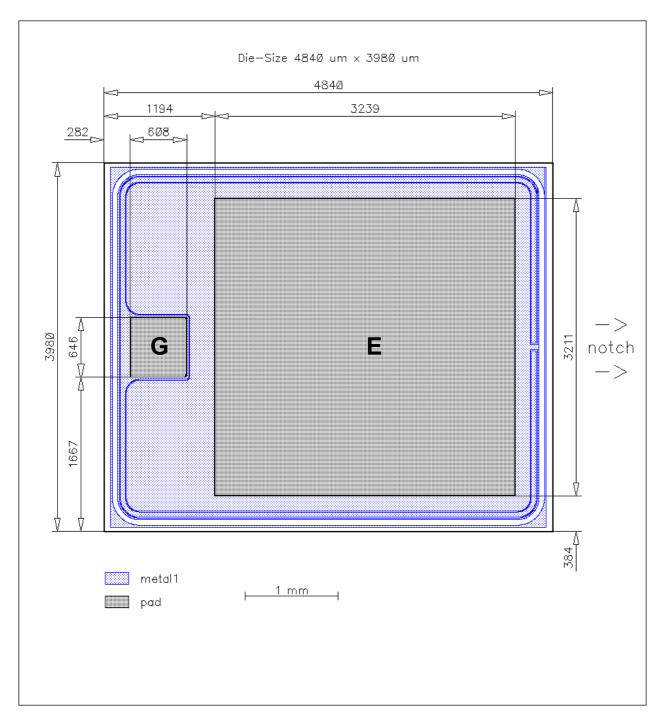
### **Further Electrical Characteristic**

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

This chip data sheet refers to the device data sheet	IHW40T60	Rev. 2.0



### **Chip Drawing**



**E** = Emitter

G = Gate



Description
AQL 0,65 for visual inspection according to failure catalogue
Electrostatic Discharge Sensitive Device according to MIL-STD 883

#### **Revision History**

Version	Subjects (major changes since last revision)	Date

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